

Supporting Information of

Entropy Engineering Enabled Atomically Dispersed Cu Doping Leading to Exceptionally High Thermoelectric Figure of Merit in n-type Lead Chalcogenides

Ziling Yuan^{1,†}, Mengyue Wu^{1,†}, Shuai Han^{1,†}, Pengfei Liu⁴, Zhenhua Ge⁵, Bangzhi Ge¹, Menghua Zhu¹, Yadong Xu¹, Wanqi Jie¹, Dongyao Zhao⁶, Bingchao Yang⁶, Yongsheng Zhang⁶, Ming Liu³, Min Zhu⁷, Chao Li^{2,*}, Yuan Yu^{3,*}, Chongjian Zhou^{1,*}

¹State Key Laboratory of Solidification Processing, and Key Laboratory of Radiation Detection Materials and Devices, Ministry of Industry and Information Technology, Northwestern Polytechnical University, Xi'an 710072, China

²The Fifth Electronics Research Institute of Ministry of Industry and Information Technology, Guangzhou 510006, China

³Institute of Physics (IA), RWTH Aachen University, 52056 Aachen, Germany

⁴Institute of High Energy Physics, Chinese Academy of Sciences, Beijing 100049, China
Spallation Neutron Source Science Center, Dongguan 523803, China

⁵Faculty of Materials Science and Engineering, Kunming University of Science and Technology, Kunming, 650093, China

⁶Laboratory of High-Pressure Physics and Material Science (HPPMS), School of Physics and Physical Engineering, Qufu Normal University, Qufu, 273165, China

⁷State Key Laboratory of Functional Materials for Informatics, Shanghai Institute of Micro-System and Information Technology, Chinese Academy of Sciences; 200050 Shanghai, China

[†]These authors contributed equally to this work

*Corresponding author. Email: cjzhou@nwpu.edu.cn, lichao@ceprei.com, yu@physik.rwth-aachen.de

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Figure S10. Experimentally measured room temperature lattice thermal conductivity (κ_{lat}) alongside transverse (v_t) and longitudinal (v_l) sound velocities of pristine PbSe and entropy-engineered samples of Cu_{0.004}Pb_{1-x}Sn_xSe_{0.5}Te_{0.25}S_{0.25} ($x = 0, 0.01, 0.05, 0.1$)

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4. References

1. Calculation Details

Calculations for Pisarenko relation based on a single Kane band model (SKB).

Pisarenko relation is calculated employing a single Kane band model, assuming acoustic phonons dominate scattering mechanism. The carrier concentration (n), Seebeck coefficient (S), carrier mobility (μ), Lorenz number (L), electrical conductivity (σ), and power factor (PF) can be approximated by the equations (1) – (5):¹

$$n = \frac{(2m^*k_B T)^{3/2}}{3\pi^2\hbar^3} {}_0F_0^{3/2} \quad (1)$$

$$S = \frac{k_B}{e} \left[\frac{{}^1F_{-2}^1}{{}_0F_{-2}^1} - \xi \right] \quad (2)$$

$$\mu = \frac{2\pi\hbar^4 e C_l}{m_l^* (2m_b^* k_B T)^{3/2} \Xi^2} \frac{3 {}^1F_{-2}^1}{{}_0F_{-2}^1} \quad (3)$$

$$L = \left(\frac{k_B}{e} \right)^2 \left[\frac{{}^2F_{-2}^1}{{}_0F_{-2}^1} - \left(\frac{{}^1F_{-2}^1}{{}_0F_{-2}^1} \right)^2 \right] \quad (4)$$

$${}^nF_k^m = \int_0^\infty \left(-\frac{\partial f}{\partial \varepsilon} \right) \varepsilon^n (\varepsilon + \alpha \varepsilon^2)^m \left[(1 + 2\alpha \varepsilon)^2 + 2 \right]^{k/2} d\varepsilon \quad (5)$$

In the equations, \hbar is the reduced Planck constant, T is the absolute temperature, k_B is the Boltzmann constant, m^* is the density of states effective mass given band degeneracy, C_l (9.1×10^{10} Pa for PbSe) is a parameter determined by combining elastic constants,² e is the elementary positive charge, α is the reciprocal reduced band gap given by $k_B T / E_g$, in which E_g is the band gap. Ξ is the deformation potentials for multivalley systems, describing carrier scattering strength by acoustic phonons.

Table S1. The formation energies of all possible crystal structures by placing Cu atom over every interstitial site in matrix.

Config	$E_{\text{formation}}$ (eV)	Config	$E_{\text{formation}}$ (eV)	Config	$E_{\text{formation}}$ (eV)	Config	$E_{\text{formation}}$ (eV)
1	1.11	33	1.10	65	1.11	97	1.24
2	1.17	34	1.27	66	1.10	98	1.08
3	1.18	35	1.09	67	1.19	99	1.16
4	1.21	36	1.18	68	1.13	100	1.15
5	1.16	37	1.26	69	1.25	101	1.24
6	1.08	38	1.13	70	1.17	102	1.21
7	1.22	39	1.25	71	1.18	103	1.14
8	1.13	40	1.20	72	1.15	104	1.28
9	1.11	41	1.20	73	1.15	105	1.10
10	1.16	42	1.31	74	1.22	106	1.10
11	1.19	43	1.13	75	1.16	107	1.25
12	1.25	44	1.07	76	1.09	108	1.26
13	1.19	45	1.24	77	1.16	109	1.23
14	1.19	46	1.22	78	1.15	110	1.12
15	1.08	47	1.10	79	1.23	111	1.24
16	1.12	48	1.16	80	1.25	112	1.22
17	1.27	49	1.17	81	1.09	113	1.27
18	1.23	50	1.14	82	1.15	114	1.17
19	1.20	51	1.16	83	1.17	115	1.21
20	1.28	52	1.14	84	1.09	116	1.26
21	1.13	53	1.18	85	1.16	117	1.09
22	1.28	54	1.27	86	1.16	118	1.14
23	1.15	55	1.17	87	1.15	119	1.15
24	1.15	56	1.16	88	1.27	120	1.14
25	1.28	57	1.11	89	1.11	121	1.23
26	1.25	58	1.12	90	1.12	122	1.17
27	1.20	59	1.15	91	1.20	123	1.24
28	1.29	60	1.16	92	1.10	124	1.27
29	1.18	61	1.19	93	1.25	125	1.13
30	1.15	62	1.16	94	1.18	126	1.11
31	1.30	63	1.29	95	1.08	127	1.16
32	1.09	64	1.31	96	1.27	128	1.18

Table S2. The calculation of band gaps and electron effective mass for PbSe, PbSe_{0.5}Te_{0.25}S_{0.25}, Pb_{0.99}Sn_{0.01}Se_{0.5}Te_{0.25}S_{0.25}, Cu_{0.004}PbSe, Cu_{0.004}Pb_{0.99}Sn_{0.01}Se, Cu_{0.004}PbSe_{0.5}Te_{0.25}S_{0.25}, Cu_{0.004}Pb_{0.99}Sn_{0.01}Se_{0.5}Te_{0.25}S_{0.25}.

Configuration	E _g (eV)	m ₀ (m _e)		
		Γ→X	Γ→R	Average
PbSe	0.448	0.142	0.124	0.133
PbSe _{0.5} Te _{0.25} S _{0.25}	0.327	0.160	0.152	0.156
Pb _{0.99} Sn _{0.01} Se _{0.5} Te _{0.25} S _{0.25}	0.205	0.160	0.153	0.1565
Cu _{0.004} PbSe	0.390	0.148	0.148	0.148
Cu _{0.004} Pb _{0.99} Sn _{0.01} Se	0.339	0.156	0.156	0.156
Cu _{0.004} PbSe _{0.5} Te _{0.25} S _{0.25}	0.311	0.175	0.160	0.1675
Cu _{0.004} Pb _{0.99} Sn _{0.01} Se _{0.5} Te _{0.25} S _{0.25}	0.199	0.155	0.154	0.1545

Table S3. The density of Cu_{0.004}Pb_{1-x}Sn_xSe_{0.5}Te_{0.25}Se_{0.25} (x = 0 – 0.1)

Sample (Sn concentration)	Density (g/cm ³)
0	7.5827
0.01	7.5980
0.05	7.7263
0.1	7.8264

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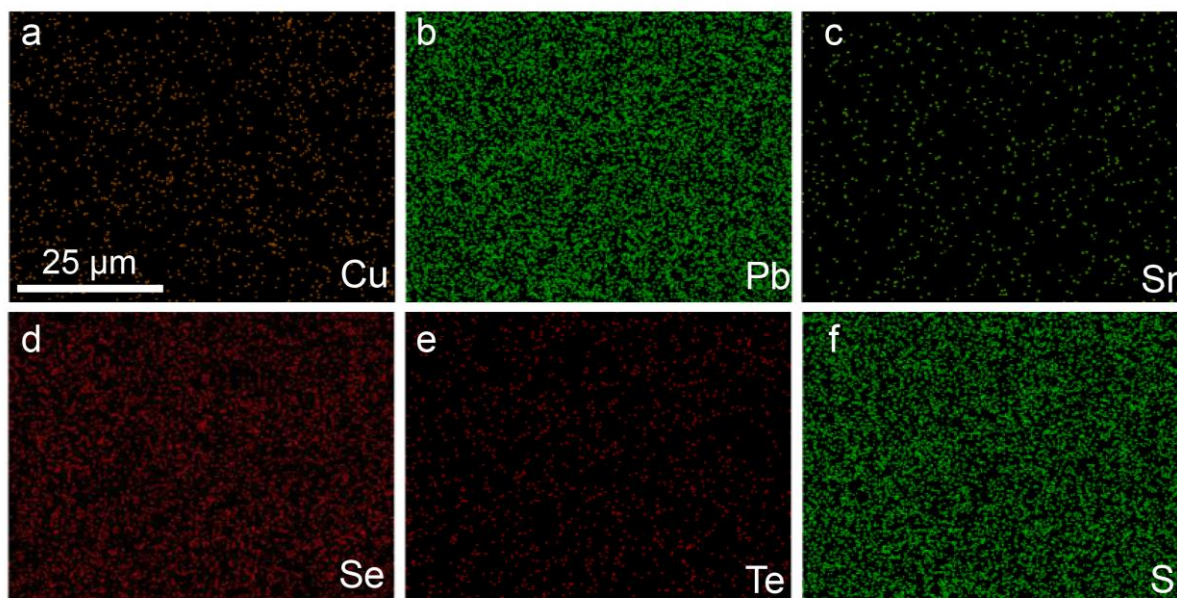


Figure S1. Energy dispersive spectrometer (EDS) image of the specimen. The corresponding EDS mappings of Cu, Pb, Sn, Se, Te and S revealing a homogeneous distribution of all elements.

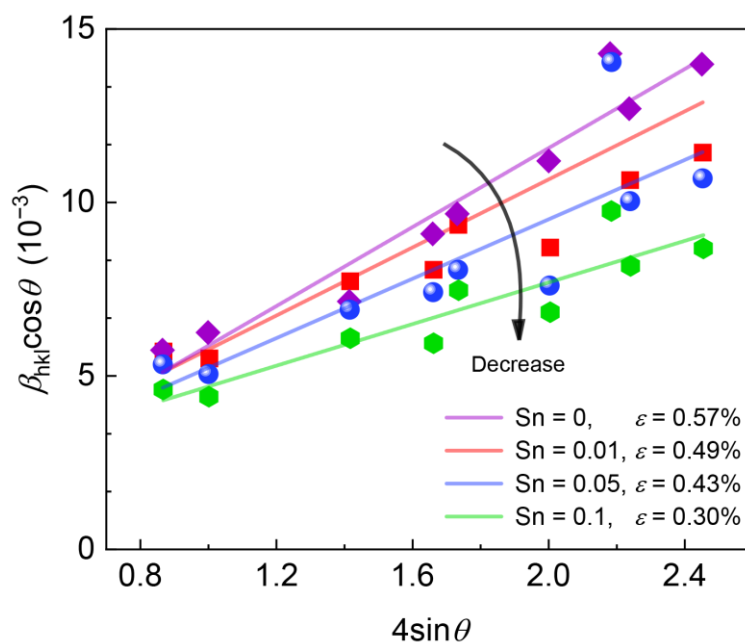


Figure S2. Williamson-Hall plot for estimating microstrain (ϵ) of entropy-engineered lead chalcogenide $\text{Cu}_{0.004}\text{Pb}_{1-x}\text{Sn}_x\text{Se}_{0.5}\text{Te}_{0.25}\text{S}_{0.25}$ ($x = 0, 0.01, 0.05, 0.1$).

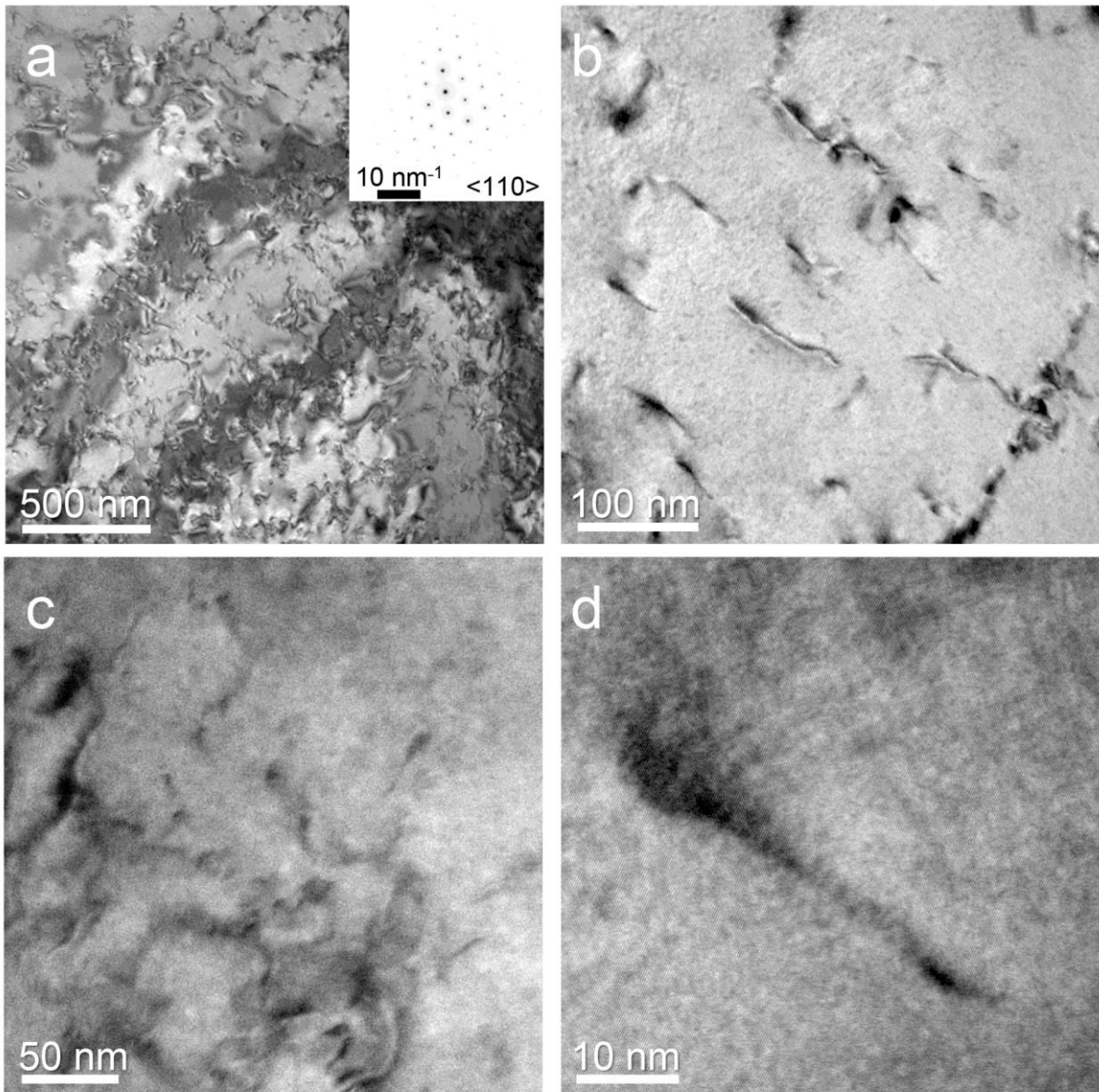


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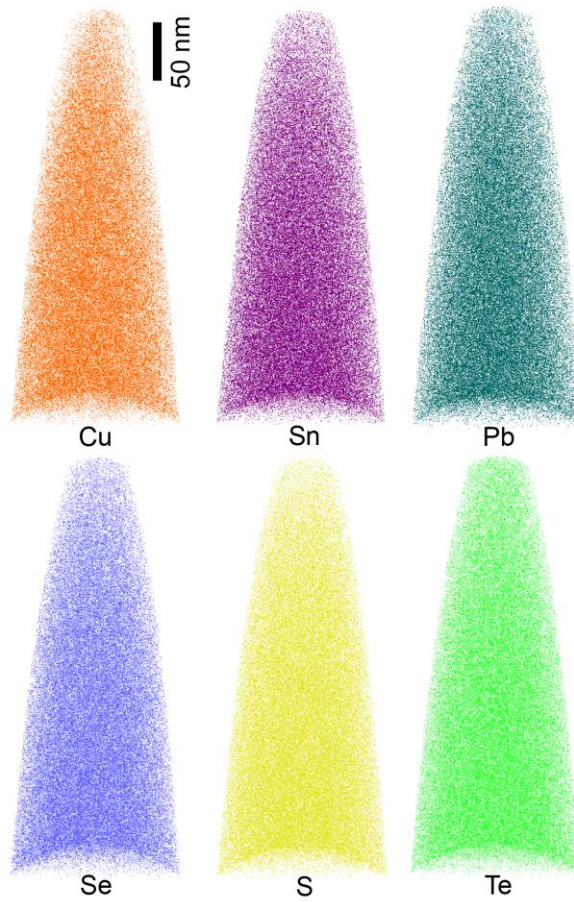


Figure S4. Three-dimensional reconstruction of needle-shaped specimen. The orange, jasper, purple, green, yellow and wine dots correspond to the Cu, Pb, Se, Te, S and Sn atoms, respectively.

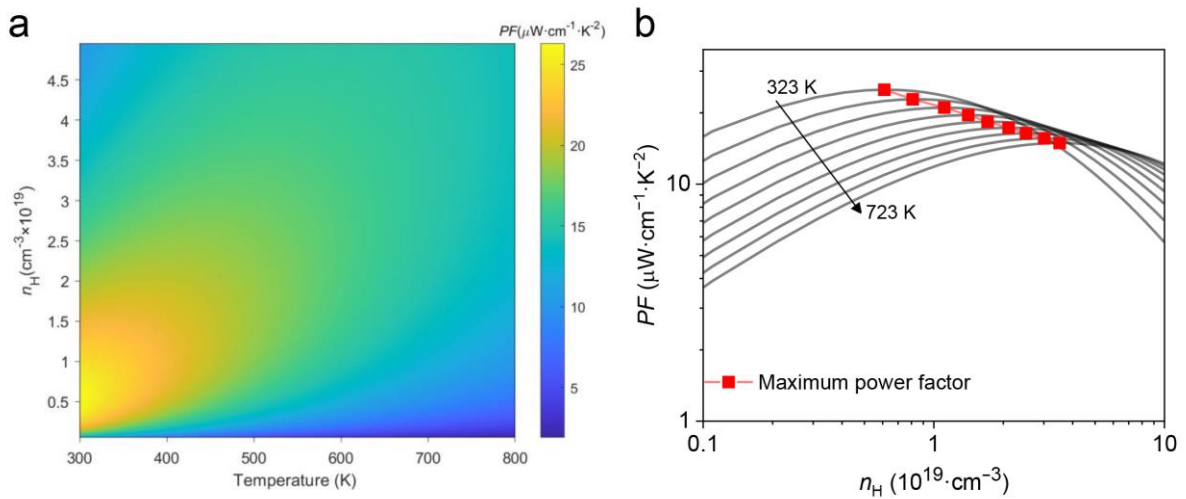


Figure S5. (a) Contour map of power factor as a function of temperature and hall carrier concentration (n_H). The colormap corresponds to changes in the PF value, with a trend towards yellow region indicating a higher PF . (b) The relationship between n_H and PF . The

red line denotes the calculated optimized PF as a function of n_H based on single Kane band (SKB) model.

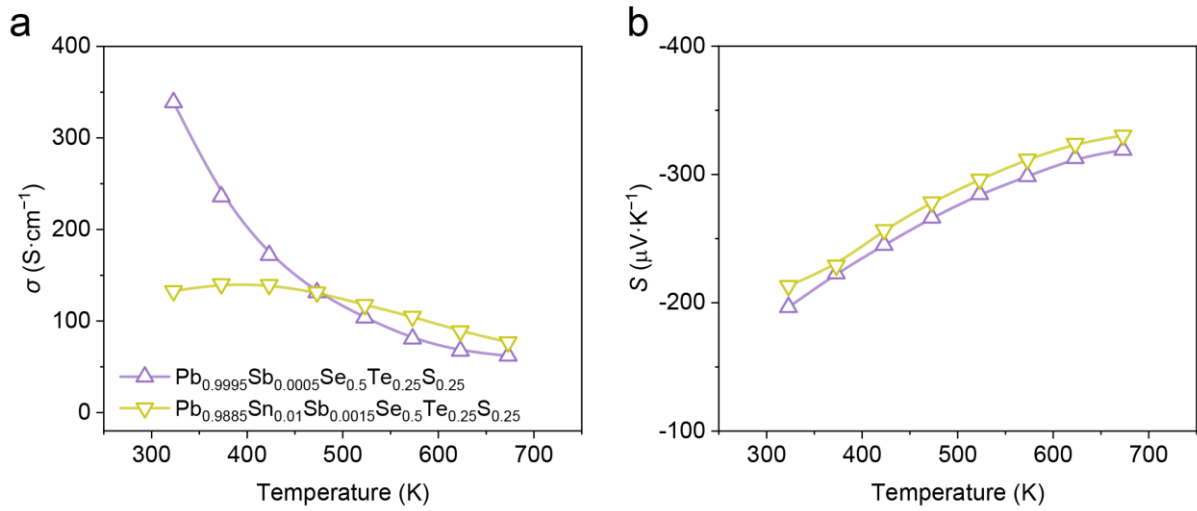


Figure S6. (a) Electrical conductivity and (b) Seebeck coefficient of $\text{Pb}_{0.9995}\text{Sb}_{0.0005}\text{Se}_{0.5}\text{Te}_{0.25}\text{S}_{0.25}$ and $\text{Pb}_{0.9885}\text{Sn}_{0.01}\text{Sb}_{0.0015}\text{Se}_{0.5}\text{Te}_{0.25}\text{S}_{0.25}$

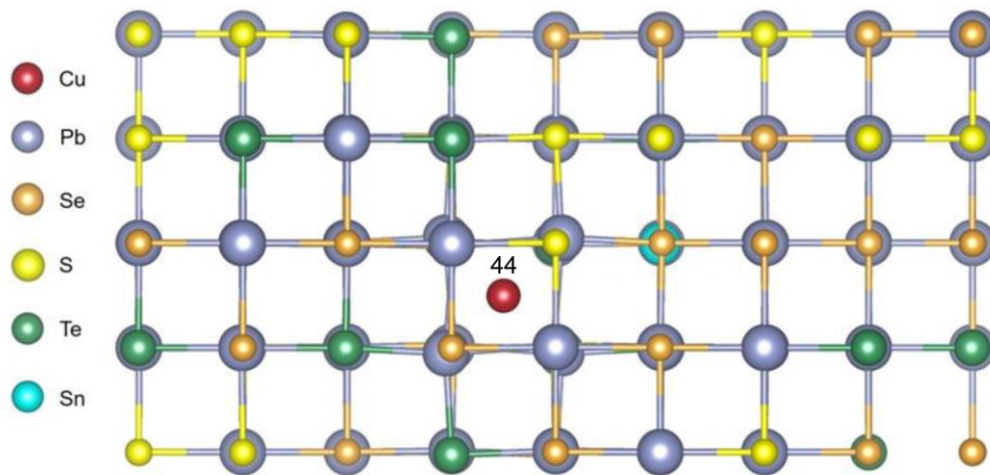


Figure S7. Crystal structure of Cu doped $\text{Pb}_{0.99}\text{Sn}_{0.01}\text{Se}_{0.5}\text{S}_{0.25}\text{Te}_{0.25}$ systems with lowest formation energy.

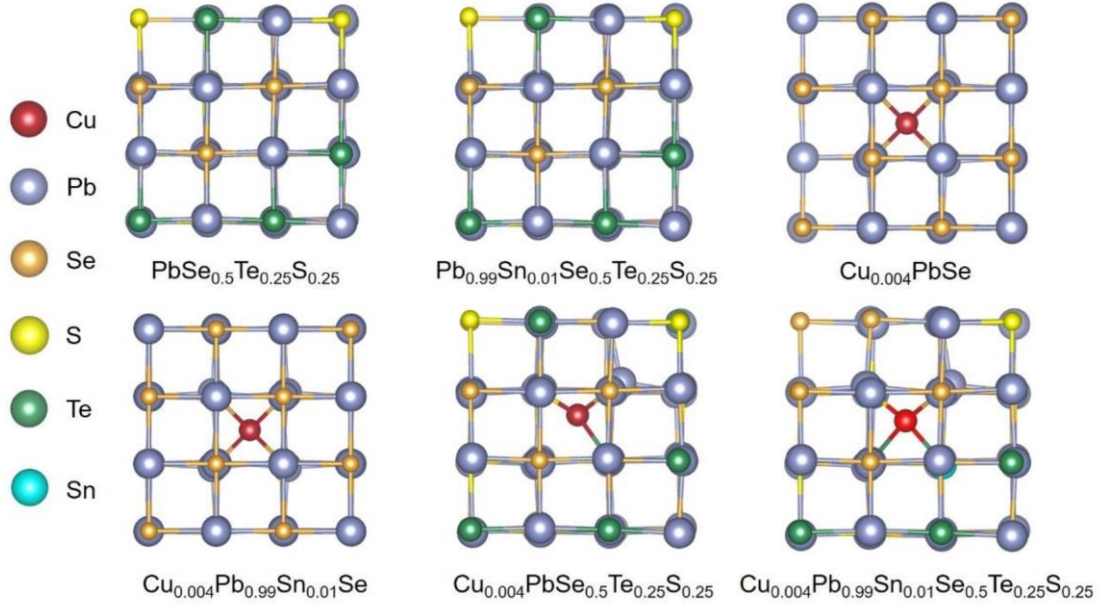


Figure S8. The structure of $\text{PbSe}_{0.5}\text{Te}_{0.25}\text{S}_{0.25}$, $\text{Pb}_{0.99}\text{Sn}_{0.01}\text{Se}_{0.5}\text{Te}_{0.25}\text{S}_{0.25}$, $\text{Cu}_{0.004}\text{PbSe}$, $\text{Cu}_{0.004}\text{Pb}_{0.99}\text{Sn}_{0.01}\text{Se}$, $\text{Cu}_{0.004}\text{PbSe}_{0.5}\text{Te}_{0.25}\text{S}_{0.25}$ and $\text{Cu}_{0.004}\text{Pb}_{0.99}\text{Sn}_{0.01}\text{Se}_{0.5}\text{Te}_{0.25}\text{S}_{0.25}$.

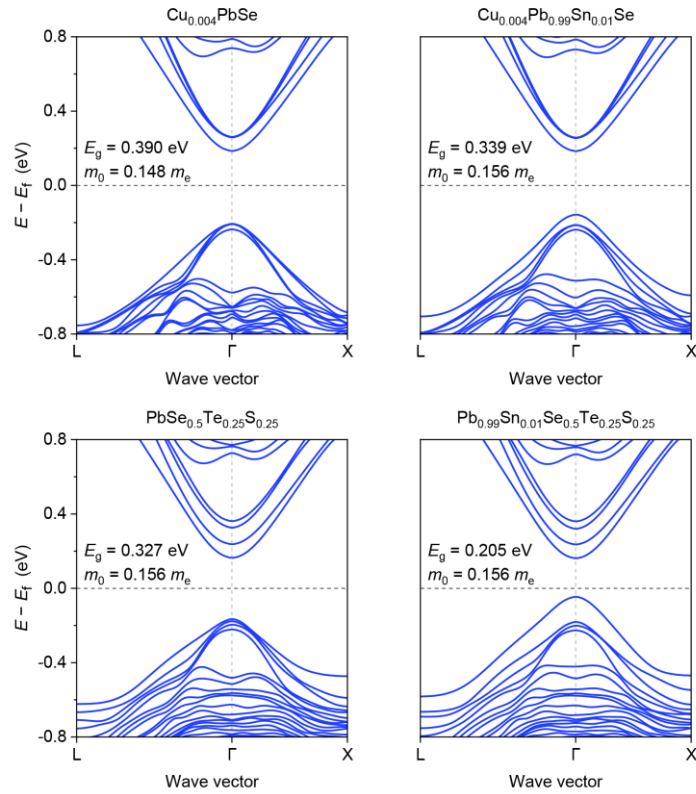


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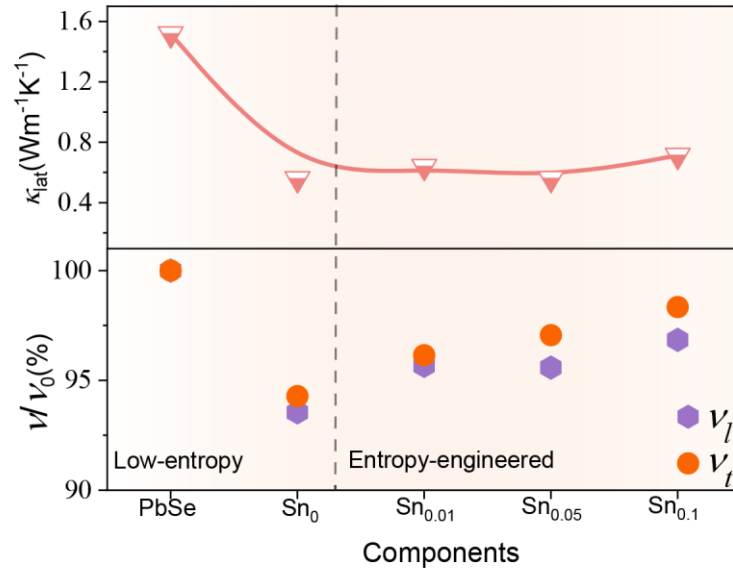


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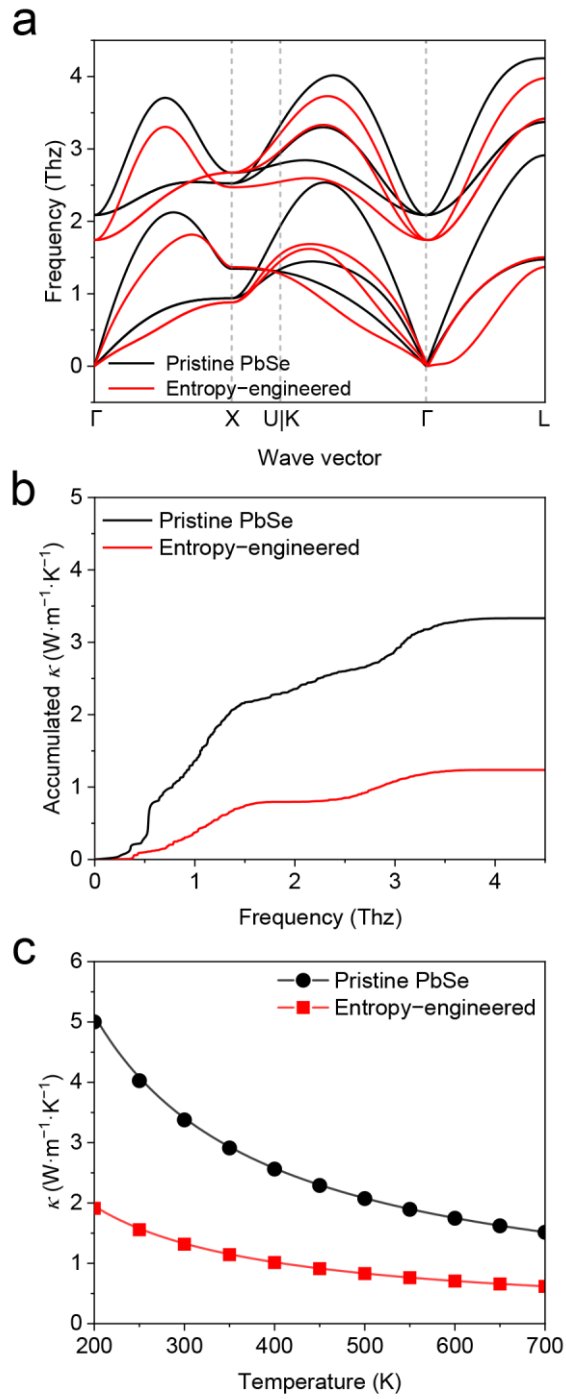


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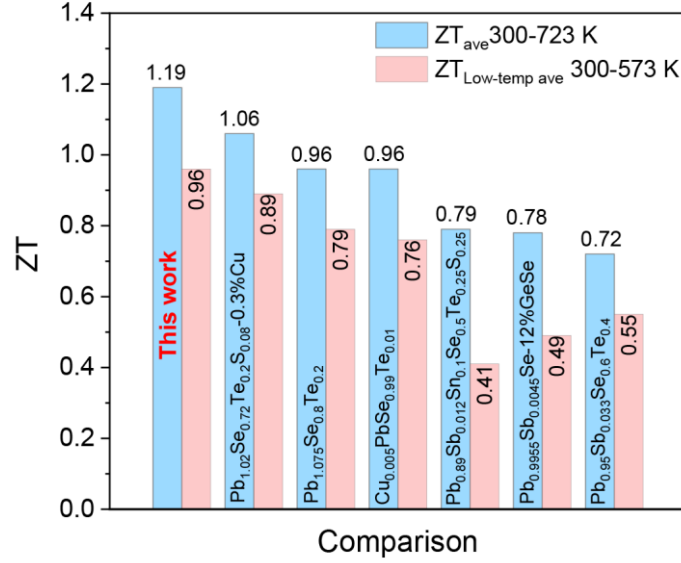


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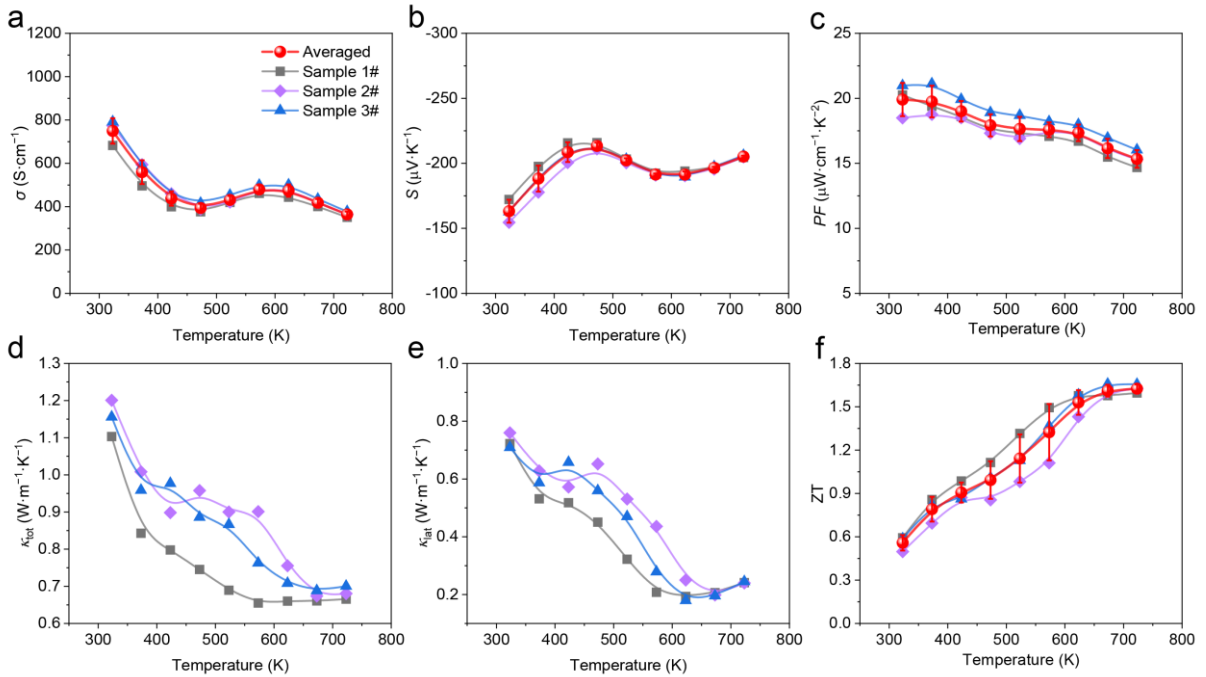


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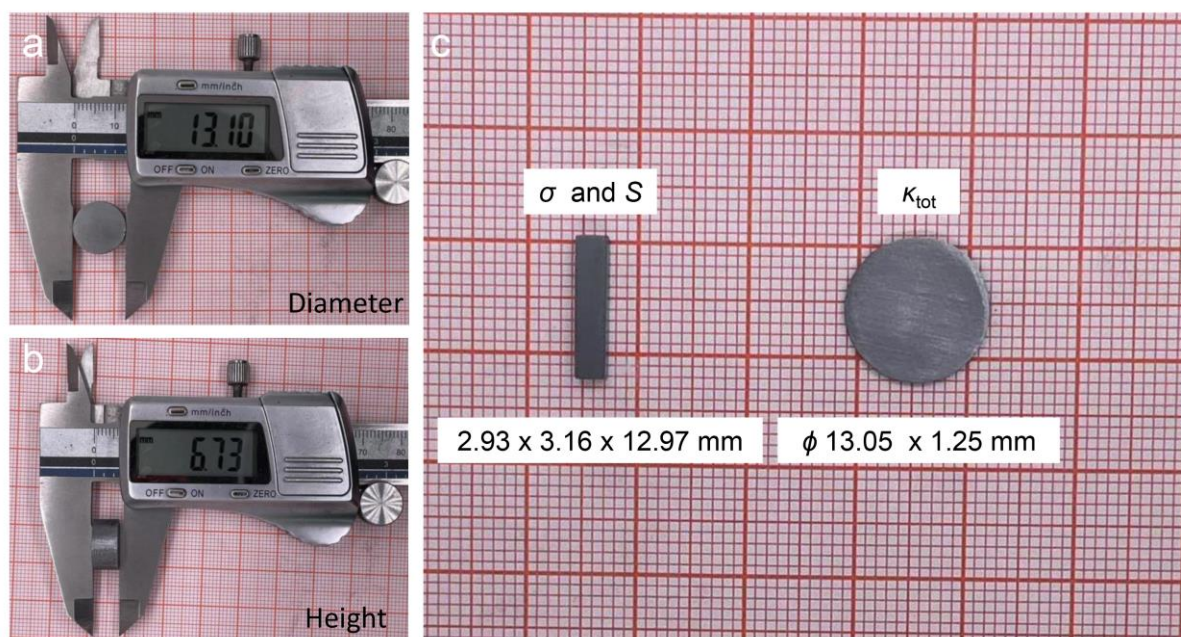


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4. References

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